



PCTEST ENGINEERING LABORATORY, INC.

6660-B Dobbin Road, Columbia, MD 21045 USA
Tel. 410.290.6652 / Fax 410.290.6654
<http://www.pctestlab.com>



MEASUREMENT REPORT FCC Part 15B

Applicant Name:

Samsung Electronics, Co. Ltd.
18600 Broadwick St.
Rancho Dominguez, CA 90220
United States

Date of Testing:

August 19 - 23, 2011

Test Site/Location:

PCTEST Lab, Columbia, MD, USA

Test Report Serial No.:

0Y1108151429.A3L

FCC ID: A3LGTI9100

APPLICANT: Samsung Electronics, Co. Ltd.

Application Type: Class II Permissive Change

EUT Type: Portable Handset

Model(s): GT-I9100M

FCC Rule Part(s): FCC Part 15 Subpart B

FCC Classification: FCC Class B Digital Device (JBP)

Test Procedure: ANSI C63.4-2003

Class II Perm. Change: Please see FCC change documents.

Original Grant Date: March 11, 2011

The device bearing the FCC Identifier specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and has been tested in accordance with the measurement procedures specified in ANSI C63.4-2003 (See Test Report). The results shown herein are also deemed satisfactory evidence of compliance with Industry Canada Interference-Causing Equipment Standard ICES-003. These measurements were performed with no deviation from the standards. Test results reported herein relate only to the item(s) tested.

I authorize and attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

NVLAP accreditation does not constitute any product endorsement by NVLAP or any agency of the United States Government. This report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government. PCTEST certifies that no party to this application has been subject to a denial of Federal benefits that includes FCC benefits pursuant to Section 5301 of the Anti-Drug Abuse Act of 1988, 21 U.S.C. 862.


Randy Ortanez
President

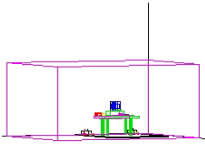

Lab Code 100431-0

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 1 of 17

TABLE OF CONTENTS

FCC Class B MEASUREMENT REPORT	3
1.0 INTRODUCTION	4
1.1 SCOPE	4
1.2 PCTEST TEST LOCATION	4
2.0 PRODUCT INFORMATION.....	5
2.1 EQUIPMENT DESCRIPTION	5
2.2 OPERATION MODE	5
2.3 EMI SUPPRESSION DEVICE(S)/MODIFICATIONS	5
2.4 LABELING REQUIREMENTS	5
3.0 DESCRIPTION OF TEST	6
3.1 EVALUATION PROCEDURE	6
3.2 RADIATED EMISSIONS.....	7
4.0 SAMPLE CALCULATIONS	8
4.1 RADIATED EMISSION MEASUREMENT SAMPLE CALCULATION.....	8
5.0 TEST EQUIPMENT CALIBRATION DATA	9
6.0 ENVIRONMENTAL CONDITIONS	10
7.0 TEST DATA.....	11
7.1 SUMMARY	11
7.2 TEST SUPPORT EQUIPMENT	11
7.3 RADIATED MEASUREMENT DATA	12
8.0 CONCLUSION.....	13
9.0 TEST SETUP PHOTOGRAPHS	14
10.0 EUT PHOTOGRAPHS	16

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset	Page 2 of 17	



MEASUREMENT REPORT

FCC Part 15B – Unintentional Radiators



§ 2.1033 General Information

APPLICANT: Samsung Electronics, Co. Ltd.

APPLICANT ADDRESS: 18600 Broadwick St.
Rancho Dominguez, CA 90220

TEST SITE: PCTEST ENGINEERING LABORATORY, INC.

TEST SITE ADDRESS: 6660-B Dobbin Road, Columbia, MD 21045 USA

FCC RULE PART(S): FCC Part 15 Subpart B

FCC ID: A3LGTI9100

Test Device Serial No.: FI-198-C ☐ Production ☒ Pre-Production ☐ Engineering

FCC CLASSIFICATION: FCC Class B Digital Device (JBP)

DATE(S) OF TEST: August 19 - 23, 2011

Test Methodology

Both conducted and radiated measurements were taken using the methods and procedures described in ANSI C63.4-2003. Radiated testing was performed at an antenna-to-EUT distance of 3 meters.

Test Facility / NVLAP Accreditation

Conducted and radiated tests were performed at PCTEST Engineering Lab in Columbia, MD 21045, U.S.A.

- PCTEST facility is an FCC registered (PCTEST Reg. No. 90864) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451A-1).
- PCTEST Lab is accredited by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP) in EMC, Telecommunication, and FCC for satisfactory compliance with criteria established in Title 15, Part 285 Code of Federal Regulations. (NVLAP Lab code: 100431-0).
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451A-1) test laboratory with the site description on file at Industry Canada.

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 3 of 17

1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 PCTEST Test Location

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity area, the Baltimore-Washington Internt'l (BWI) airport, the city of Baltimore and the Washington, DC area. (see Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility in New Concept Business Park, Guilford Industrial Park, Columbia, Maryland. The site address is 6660-B Dobbin Road, Columbia, MD 21045. The test site is one of the highest points in the Columbia area with an elevation of 390 feet above mean sea level. The site coordinates are 39° 11'15" N latitude and 76° 49'38" W longitude. The facility is 1.5 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. There are no FM or TV transmitters within 15 miles of the site. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on January 28, 2009.

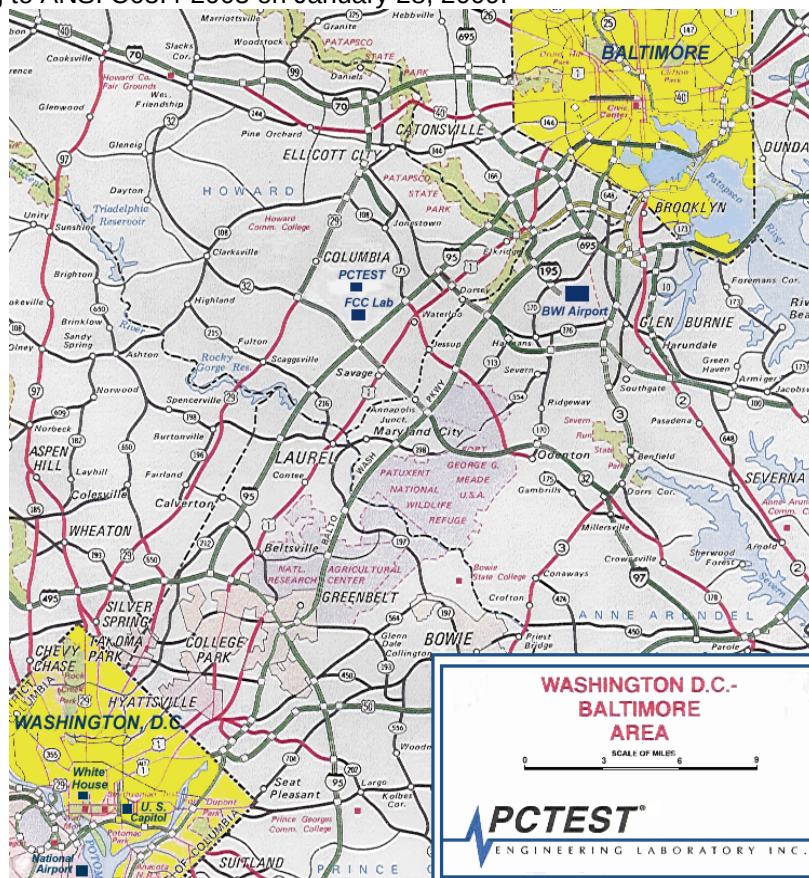


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

FCC ID: A3LGTI9100	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 4 of 17

2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LGTI9100**. The test data contained in this report pertains only to the emissions due to the digital circuitry of the EUT.

Manufacturer / Base Model	FCC ID	Description
Samsung / Model: GT-I9100M	A3LGTI9100	Portable Handset

Table 2-1. EUT Equipment Description

2.2 Operation Mode

The Samsung Portable Handset FCC ID: A3LGTI9100 was tested with a NOTEBOOK connected via USB interface port. The EUT was exercised during testing by means of software installed on the notebook. For more information please see Section 7.0 for test data and Sections 9.0 and 10.0 for the test setup photographs.

2.3 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.4 Labeling Requirements

Per 15.19; Docket 95-19

The label shall be permanently affixed at a conspicuous location on the device; instruction manual or pamphlet supplied to the user and be readily visible to the purchaser at the time of purchase. However, when the device is so small wherein placement of the label with specified statement is not practical, only the trade name and FCC ID must be displayed on the device per Section 15.19(b)(2).

Please see attachment for FCC ID label and label location.

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 5 of 17

3.0 DESCRIPTION OF TEST

3.1 Evaluation Procedure

The measurement procedure described in the American National Standard for Methods of Measurement of Radio-Noise Emission from Low-Voltage Electrical and Electronic Equipment in the Range of 9kHz to 40GHz (ANSI C63.4-2003) was used in the measurement of the **Samsung Portable Handset FCC ID: A3LGTI9100**.

Deviation from measurement procedure.....None

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 6 of 17

3.2 Radiated Emissions

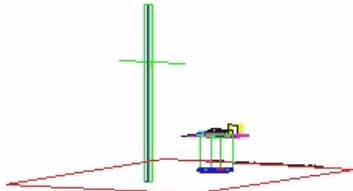


Figure 3-1. 3-Meter Test Site

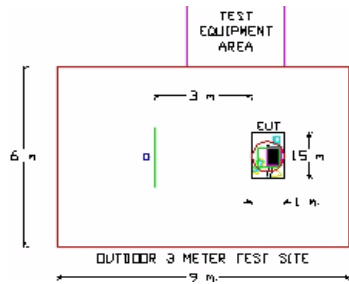


Figure 3-2. Dimensions of Outdoor Test Site

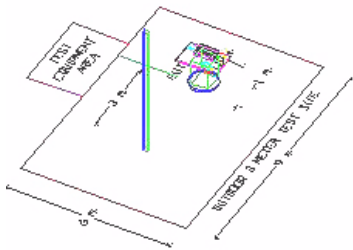


Figure 3-3. Turntable and System Setup

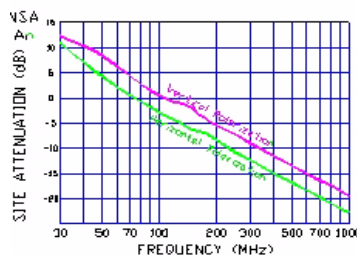


Figure 3-4. Normalized Site Attenuation Curves (H&V)

Preliminary measurements were made indoors at 1-meter using broadband antennas, broadband amplifiers, and spectrum analyzers to determine the frequency producing the maximum EME. Appropriate precaution was taken to ensure that all EME from the EUT were maximized and investigated. The system configuration, clock speed, mode of operation or video resolution, and turntable azimuth with respect to the antenna was noted for each frequency found. The spectrum was scanned from 30 to 200 MHz using a bi-conical antenna and from 200 to 1000 MHz using a log-spiral antenna. Above 1 GHz, linearly polarized double ridge horn antennas were used.

Final measurements were made outdoors at 3-meter test range using RobertsTM Dipole antennas or horn antennas (see Figure 3-1). The test equipment was placed on a wooden and plastic bench situated on a 1.5m x 2m area adjacent to the measurement area (see Figure 3-2). Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The detector function was set to CISPR quasi-peak mode and the bandwidth of the spectrum analyzer was set to 100kHz for frequencies below 1GHz or 1MHz for frequencies above 1GHz. Above 1GHz the detector function was set to average mode (RBW = 1MHz, VBW = 10Hz).

The half-wave dipole antenna was tuned to the frequency found during preliminary radiated measurements. The EUT, support equipment and interconnecting cables were re-configured to the set-up producing the maximum emission for the frequency and were placed on top of a 0.8-meter high non-metallic 1 x 1.5 meter table (see Figure 3-3). The EUT, support equipment, and interconnecting cables were re-arranged and manipulated to maximize each EME emission. The turntable containing the system was rotated and the height of the receive antenna was varied 1 to 4 meters and stopped at the azimuth and height producing the maximum emission. Each emission was maximized by: varying the mode of operation or resolution; clock or data exchange speed; scrolling H pattern to the EUT and/or support equipment, and powering the monitor from the floor mounted outlet box and the computer aux AC outlet, if applicable; and changing the polarity of the antenna, whichever determined the worst-case emission. Photographs of the worst-case emission can be seen in the test setup photographs. Each EME reported was calibrated using the Agilent E8257D (250kHz – 20GHz) PSG Signal Generator. The Theoretical Normalized Site Attenuation Curves for both horizontal and vertical polarization are shown in Figure 3-4.

FCC ID: A3LGTI9100	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 7 of 17

4.0 SAMPLE CALCULATIONS

4.1 Radiated Emission Measurement Sample Calculation

@ 66.7 MHz

Class B limit	= 100 $\mu\text{V/m}$ = 40.0 dB $\mu\text{V/m}$
Reading	= - 76.0 dBm (calibrated level)
Convert to dB μV	= - 76.0 + 107 = 31.0 dB μV
Antenna Factor + Cable Loss	= 5.8 dB/m
Total	= 36.8 dB $\mu\text{V/m}$
Margin	= 36.8 - 40.0 = - 3.2 dB
	= 3.2 dB below limit

Note:

$$\text{Level [dB}\mu\text{V]} = 20 \log_{10} (\text{Level } [\mu\text{V/m}])$$
$$\text{Level [dB}\mu\text{V]} = \text{Level [dBm]} + 107$$

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 8 of 17

5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	No.166	(1000-26500MHz) Microwave RF Cable	N/A		N/A	N/A
-	No.167	(100kHz - 100MHz) RG58 Coax Cable	N/A		N/A	N/A
Agilent	8447D	Broadband Amplifier	3/17/2011	Annual	3/17/2012	1937A03348
Agilent	8447D	Broadband Amplifier	3/17/2011	Annual	3/17/2012	2443A01900
Agilent	8449B	(1-26.5GHz) Pre-Amplifier	2/8/2011	Annual	2/8/2012	3008A00985
Agilent	85650A	Quasi-Peak Adapter	4/7/2011	Annual	4/7/2012	3303A01872
Agilent	85650A	Quasi-Peak Adapter	4/7/2011	Annual	4/7/2012	2043A00301
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	2618A02866
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	2542A11898
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	3638A08713
Agilent	E4407B	ESA Spectrum Analyzer	4/5/2011	Annual	4/5/2012	US39210313
Agilent	E4448A	PSA (3Hz-50GHz) Spectrum Analyzer	11/30/2010	Annual	11/30/2011	US42510244
Agilent	E8257D	(250kHz-20GHz) Signal Generator	4/8/2011	Annual	4/8/2012	MY45470194
Agilent	N9038A	MXE EMI Receiver	8/5/2011	Annual	8/5/2012	MY51210133
Compliance Design	Roberts	Dipole Set	4/7/2010	Biennial	4/7/2012	146
Compliance Design	Roberts	Dipole Set	4/7/2010	Biennial	4/7/2012	147
Emco	6502	Active Loop Antenna (10k - 30 MHz)	4/8/2010	Biennial	4/8/2012	267
Emco	3816/2	LISN	11/5/2010	Biennial	11/5/2012	9707-1077
Emco	3816/2	LISN	11/3/2010	Biennial	11/3/2012	9707-1079
Pasternack	PE7000-6	6 dB Attenuator	N/A		N/A	N/A
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	9/17/2009	Biennial	9/17/2011	A051107
Sunol	DRH-118	Horn Antenna (1-18 GHz)	6/17/2011	Biennial	6/17/2013	A042511

Table 5-1. Annual Test Equipment Calibration Schedule

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 9 of 17

6.0 ENVIRONMENTAL CONDITIONS

The temperature is controlled within range of 15°C to 35°C.

The relative humidity is controlled within range of 10% to 75%.

The atmospheric pressure is controlled within the range 86-106kPa (860-1060mbar).

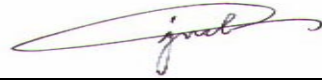
FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 10 of 17

7.0 TEST DATA

7.1 Summary

Test Date(s): August 19 - 23, 2011

Test Engineer:



FCC Part 15 Section	Description	Result
15.107	Conducted Emissions	PASS
15.109	Radiated Emissions	PASS

Table 7-1. Summary of Test Results

7.2 Test Support Equipment

1	Samsung Data Cable	Model: ECC1DU4BBE 1.0m Shielded USB Data Cable	S/N: N/A
2	Panasonic Toughbook #2 w/ Panasonic AC Adapter	FCC ID: ACJ9TGCF-513 Model: CF-AA1683A 2.0m Unshielded AC power cord 2.0m Unshielded DC power cord with ferrite bead on notebook end	S/N: 7ATYA28277R S/N: 1683AM306Y01583D
3	Dynex USB PC Camera	Model: DX-WC101 (DoC) 2.07m Shielded USB Cable	S/N: 122D05AC

Note: See test setup photographs for actual system test setup.

7.3 Radiated Measurement Data

§15.109; RSS-Gen (6(a))

Frequency [MHz]	Level [dBm]	AFCL [dB]	Pol [H/V]	Height [m]	Azimuth [degrees]	Field Strength [dB μ V/m]	Limit [dB μ V/m]	Margin [dB]
45.52	-99.54	11.18	H	1.2	120	18.65	40.00	-21.35
177.44	-98.56	14.21	H	1.3	225	22.65	43.52	-20.87
218.18	-98.58	14.24	H	1.3	185	22.66	46.02	-23.36
326.82	-97.28	16.89	V	1.4	95	26.61	46.02	-19.41
348.16	-95.22	17.47	H	1.2	135	29.24	46.02	-16.78
681.84	-97.94	23.77	V	1.4	320	32.84	46.02	-13.18

Table 7-2. Radiated Measurements at 3-meters

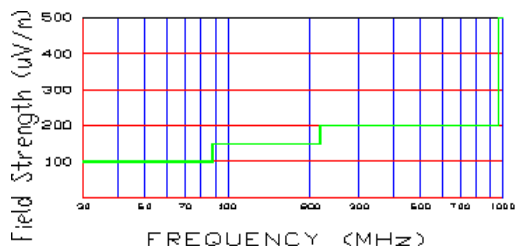


Figure 7-1. 3 Meter Limits

NOTES:

1. All modes of operation were investigated and the worst-case emissions are reported.
2. Radiated Emissions were measured from 30MHz – 2000MHz.
3. The radiated limits are shown on Figure 7-1. Above 960MHz the limit is 500 μ V/m.

1. All readings are calibrated by Agilent E8257D (250kHz – 20GHz) PSG Signal Generator with accuracy traceable to the National Institute of Standards and Technology (NIST).
2. AFCL = Antenna Factor and Cable Loss
3. Measurements made using CISPR quasi-peak mode. Above 1GHz, peak detector function mode is used with a resolution bandwidth of 1MHz and a video bandwidth of 1MHz. The peak level complies with the average limit. Peak mode is used with linearly polarized horn antenna and low-loss microwave cable.

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 12 of 17

8.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LGTI9100** has been tested to comply with the requirements specified in §15.107 and §15.109 of the FCC Rules and Industry Canada Standard ICES-003.

FCC ID: A3LGTI9100		FCC Pt. 15B MEASUREMENT REPORT (CLASS II PERMISSIVE CHANGE)		Reviewed by: Quality Manager
Test Report S/N: 0Y1108151429.A3L	Test Dates: August 19 - 23, 2011	EUT Type: Portable Handset		Page 13 of 17